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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

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1200V, 85A,  $V_{ce(on)}$  = 2.5V Typical

## Ultra Fast NPT - IGBT®

The Ultra Fast NPT - IGBT® is a new generation of high voltage power IGBTs. Using Non-Punch-Through Technology, the Ultra Fast NPT-IGBT® offers superior ruggedness and ultrafast switching speed.

#### **Features**

- · Low Saturation Voltage
- Low Tail Current
- RoHS Compliant

- · Short Circuit Withstand Rated
- High Frequency Switching
- Ultra Low Leakage Current



Unless stated otherwise, Microsemi discrete IGBTs contain a single IGBT die. This device is recommended for applications such as induction heating (IH), motor control, general purpose inverters and uninterruptible power supplies (UPS).



#### **MAXIMUM RATINGS**

MAXIMUN	I <b>RATINGS</b> All Ratings: $T_C$ =	25°C unless otherwise specified.		
Symbol	Parameter	Ratings	Unit	
V <sub>ces</sub>	Collector Emitter Voltage	1200	V	
$V_{\rm GE}$	Gate-Emitter Voltage	±30		
I <sub>C1</sub>	Continuous Collector Current @ T <sub>C</sub> = 25°C	118		
I <sub>C2</sub>	Continuous Collector Current @ T <sub>c</sub> = 75°C	85	Α	
I <sub>CM</sub>	Pulsed Collector Current ①	340		
SCWT	Short Circuit Withstand Time: $V_{CE} = 600V$ , $V_{GE} = 15V$ , $T_{C} = 125$ °C	10	μs	
$P_{\scriptscriptstyle D}$	Total Power Dissipation @ T <sub>c</sub> = 25°C	595	W	
T <sub>J</sub> ,T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55 to 150	°C	
T <sub>L</sub>	Max. Lead Temp. for Soldering: 0.063" from Case for 10 Sec.	300		

#### STATIC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Min	Тур	Max	Unit
V <sub>(BR)CES</sub>	Collector-Emitter Breakdown Voltage (V <sub>GE</sub> = 0V, I <sub>C</sub> = 1.0mA)	1200			
V <sub>GE(TH)</sub>	Gate Threshold Voltage $(V_{CE} = V_{GE}, I_{C} = 2.5 \text{mA}, T_{j} = 25 ^{\circ}\text{C})$	3.5	5.0	6.5	Volts
V <sub>CE(ON)</sub>	Collector-Emitter On Voltage ( $V_{GE} = 15V$ , $I_{C} = 85A$ , $T_{j} = 25^{\circ}C$ )	ĺ	2.5	3.2	
	Collector-Emitter On Voltage ( $V_{GE} = 15V$ , $I_{C} = 85A$ , $T_{j} = 125^{\circ}C$ )		3.3		
	Collector-Emitter On Voltage (V <sub>GE</sub> = 15V, I <sub>C</sub> = 170A, T <sub>j</sub> = 25°C)		3.5		
I <sub>CES</sub>	Collector Cut-off Current (V <sub>CE</sub> = 1200V, V <sub>GE</sub> = 0V, T <sub>j</sub> = 25°C) ②		10	1000	μA
	Collector Cut-off Current (V <sub>CE</sub> = 1200V, V <sub>GE</sub> = 0V, T <sub>j</sub> = 125°C) ②		100		
I <sub>GES</sub>	Gate-Emitter Leakage Current (V <sub>GE</sub> = ±20V)			±250	nA

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

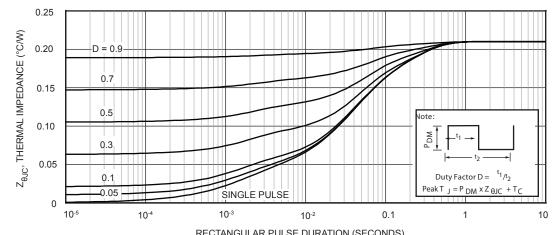
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
C <sub>ies</sub>	Input Capacitance	Capacitance		8400		
C <sub>oes</sub>	Output Capacitance	$V_{GE} = 0V, V_{CE} = 25V$		725		pF
C <sub>res</sub>	Reverse Transfer Capacitance	f = 1MHz		190		
$V_{GEP}$	Gate to Emitter Plateau Voltage	Cata Charra		7.5		V
Q3	Total Gate Charge	Gate Charge		490	660	
$Q_{ge}$	Gate-Emitter Charge	V <sub>GE</sub> = 15V		60	85	0
$Q_{gc}$	Gate- Collector Charge	$V_{CE} = 600V$ $I_{C} = 85A$		230	320	nC
t <sub>d(on)</sub>	Turn-On Delay Time	Inductive Switching (25°C)		43		
t <sub>r</sub>	Current Rise Time	V <sub>CC</sub> = 600V		70		20
$t_{d(off)}$	Turn-Off Delay Time	V <sub>GE</sub> = 15V		300		ns
t <sub>f</sub>	Current Fall Time	I <sub>C</sub> = 85A		85		
E <sub>on2</sub> ⑤	Turn-On Switching Energy	$R_{_{\rm G}} = 4.3  \Omega^{(4)}$		6000	9000	1
E <sub>off</sub>	Turn-Off Switching Energy	T <sub>J</sub> = +25°C		3800	5700	μJ
t <sub>d(on)</sub>	Turn-On Delay Time	Inductive Switching (125°C)		43		
t <sub>r</sub>	Current Rise Time	V <sub>CC</sub> = 600V		70		20
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GE</sub> = 15V		350		ns
t <sub>f</sub>	Current Fall Time	I <sub>C</sub> = 85A		95		
E <sub>on2</sub> 5	Turn-On Switching Energy	$R_{_{\rm G}} = 4.3 \ \Omega^{\textcircled{4}}$		7800	11,700	1
E <sub>off</sub>	Turn-Off Switching Energy	T <sub>J</sub> = +125°C		4900	7350	μJ

#### THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	Min	Тур	Max	Unit
$R_{_{\theta JC}}$	Junction to Case	-	-	0.21	°C/W
W <sub>T</sub>	Package Weight	-	1.03	-	OZ
Torque	Terminals and Mounting Screws.	-	-	10	in∙lbf
		-	-	1.1	N·m
V	RMS Voltage (50-60Hz Sinusoidal Waveform from Terminals to Mounting Base for 1 Min.)	2500	-	-	Volts

- 1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- 2 Pulse test: Pulse Width <  $380\mu s$ , duty cycle < 2%.
- 3 See Mil-Std-750 Method 3471.
- 4  $\,$  R $_{\rm G}$  is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)
- 5  $E_{\text{on2}}$  is the energy loss at turn-on and includes the charge stored in the freewheeling diode.
- 6 E<sub>off</sub> is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1.

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



RECTANGULAR PULSE DURATION (SECONDS)
Figure 1, Maximum Effective Transient Thermal Impedance, Junction-To-Case vs Pulse Duration

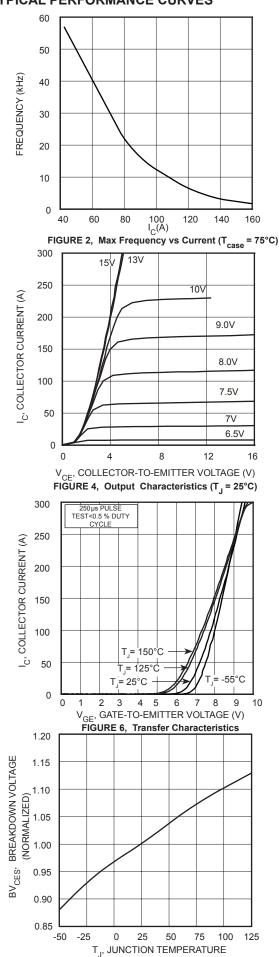


FIGURE 8, Breakdown Voltage vs Junction Temperature

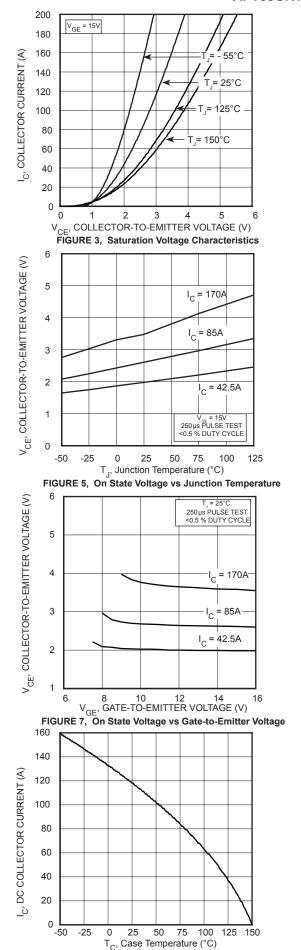


FIGURE 9, DC Collector Current vs Case Temperature

FIGURE 16, Switching Energy vs Junction Temperature

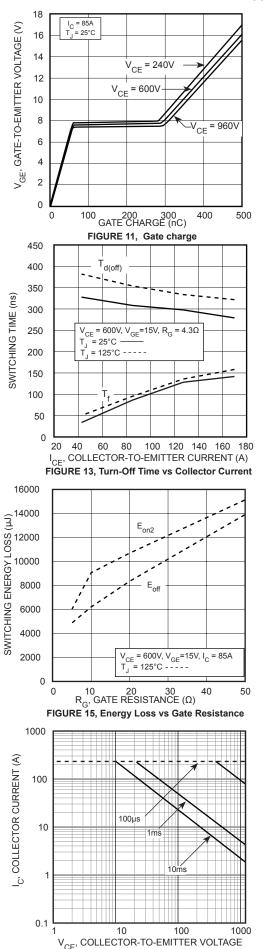
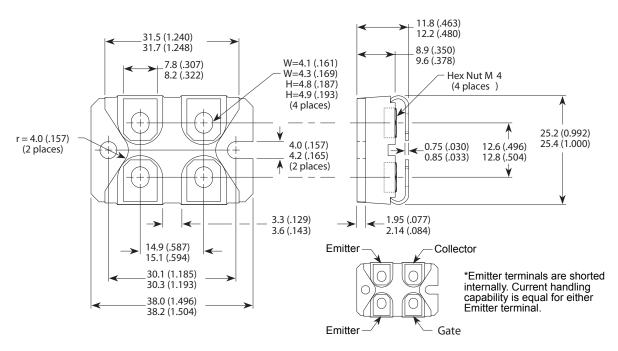


FIGURE 17, Minimum Switching Safe Operating Area

### SOT-227 (ISOTOP®) Package Outline



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